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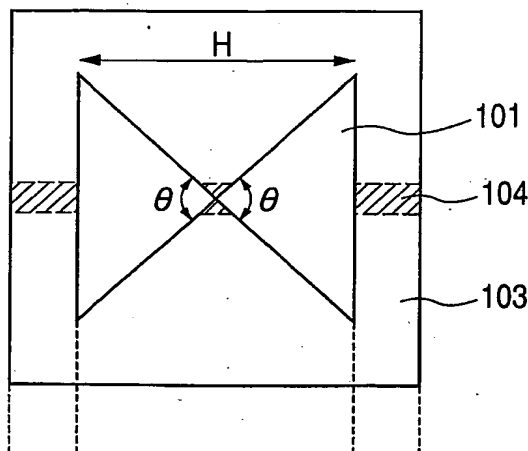
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(54) Title: INSPECTION APPARATUS USING TERAHERTZ WAVES



(57) Abstract: There is provided an inspection
apparatus having a configuration which can suppress
attenuation of an electromagnetic wave caused by
an environment surrounding the inspection apparatus
and can readily prevent an unwanted substance from
being contaminated into a propagation path of the
electromagnetic wave. The inspection apparatus 100
includes a substrate 103 having therein a structure for
holding an inspected object 104, an electromagnetic
wave transmitting portion 101 having an antenna
structure, and an electromagnetic wave receiving
portion 102 having an antenna structure. The
electromagnetic wave transmitting portion 101 and
the electromagnetic wave receiving portion 102 are
disposed in contact with the substrate 103.

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